FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTORNEY DOCKET NO. 826.1767	APPLICATION NO.
LIST OF REFERENCES CITED BY APPLICANT	FIRST NAMED INVENTOR Kwame Osei BOATENG	
(Use several sheets if necessary)	FILING DATE November 5, 2001	GROUP ART UNIT 2825

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES	TRANSLATION NO
	AG							
	AH							
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	AL							

OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

9/5	AM	K. O. Boateng, H. Takahashi and Y. Takamatsu, "Diagnosing Delay Faults in Combinational Circuits Under the Ambiguous Delay Model," IEICE Transaction on Information and Systems, Vol. E82-D, No. 12, pp. 1563-1571. Dec 1999.
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EXAMINER VUTHE SIEK	DATE CONSIDERED 6/14/05

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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LIST OF REFERENCES CITED BY APPLICANT	FIRST NAMED INVENTOR Kwame Osei BOATENG	
(Use several sheets if necessary)	FILING DATE November 5, 2001	GROUP ART UNIT 2826

Jc542 U.S. PTO 09/985768 11/06/01

U.S. PATENT DOCUMENTS

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VS	AM	I. Pomeranz and S. M. Reddy, "On Test Compaction Objectives for Combinational and Sequential Circuits," Proceedings of IEEE International Conference on VLSI Design, pp. 279-284. 1997
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EXAMINER NUTHE SIEK	DATE CONSIDERED 6/14/05

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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTORNEY DOCKET NO. 826.1767	APPLICATION NO.
LIST OF REFERENCES CITED BY APPLICANT	FIRST NAMED INVENTOR Kwame Osei BOATENG	
(Use several sheets if necessary)	FILING DATE November 5, 2001	GROUP ART UNIT 1756

1044 U.S. PTO 09/985768 11/06/01

U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

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VS	AM	M. S. Hsiao and S. T. Chakradhar, "Partitioning and Reordering Techniques for Static Test Sequence Compaction of Sequential Circuits," Proceedings of the 7th IEEE Asian Test Symposium, pp. 452-457. 1998.
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EXAMINER VUTHE SIEK	DATE CONSIDERED 6/14/05

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